



ITW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Khalder S. Abdel-Hafez et al
Serial No. 10/762,571

Group Art Unit 2857

Filed: January 23, 2004

For: Method and Apparatus for Debug, Diagnosis, and Yield Improvement for
Scan-Based Integrated Circuits

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of international application;
or before mailing date of first Office action on the merits; whichever occurs last.)
- ☐ under 37 CFR 1.97(c) together with either a:
☐ Certification under 37 CFR 1.97(e), or
☐ a \$180.00 fee under 37 CFR 1.17(p), or
(After the CFR 1.97(b) time period, but before final action or notice of allowance,
whichever occurs first.)
- ☐ under 37 CFR 1.97(d) together with either a:
☐ Certification under 37 CFR 1.97(e), and
☐ a petition under 37 CFR 1.97(d)(2)(ii), and
☐ a \$130.00 petition fee set forth in 37 CFR §117(i)(1).
(Filed after final action or notice of allowance, whichever occurs first, but before
payment of the issue fee.)

Applicant(s) submits herewith Form PTO 1449-Information Disclosure Citation together with copies of patents, publications or other information of which applicant(s) is aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

The relevance of the attached references is that this is the closest art of which applicant(s) is aware.

Applicant(s) submits that the above references taken alone or in combination neither anticipate nor render obvious the present invention. Consideration of the foregoing in relation to this application is respectfully requested.

Respectfully submitted,

Jim Zegeer
Jim Zegeer, Reg. No. 18,957
Attorney for Applicant(s)

Attachments:

Form PTO-1449 and cited references

Suite 108
801 North Pitt Street
Alexandria, VA 22314
Telephone: 703-684-8333
Date: October 27, 2004

In the event this paper is deemed not timely filed,
the applicant hereby petitions for an appropriate
extension of time. The fee for this extension may
be charged to Deposit Account No. 26-0090 along
with any other additional fees which may be
required with respect to this paper.

FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeATTY. DOCKET NO.
3380-Z

SERIAL NO.

10/762,571**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

APPLICANT

Khader S. Abdel-Hafez et al

FILING DATE

January 23, 2004

GROUP

2857**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	US 2002/0188903 A1	12/2002	Chu et al	714	738	
	US 2003/0115521 A1	06/2003	Rajski et al	714	724	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	Ghosh-Dastidar et al, "A Rapid and Scalable Diagnosis Scheme for BIST Environments with a Large Number of Scan Chains", Proc., IEEE VLSI Test Symposium (VTS), pp. 79-85, 2000.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.